United States Patent [19]

Sakihara

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[45] **Date of Patent: ** Dec. 13, 1988**

[54] **HOLDER FOR TESTING AN INTEGRATED CIRCUIT CHIP**

[75] Inventor: **Yoshinobu Sakihara,** Los Angeles, Calif.

[73] Assignee: **Vanguard Electronics Company, Inc.,** Gardena, Calif.

[**] Term: **14 Years**

[21] Appl. No.: **825,804**

[22] Filed: **Feb. 4, 1986**

[52] **U.S. Cl.** **D10/80**

[58] **Field of Search** ..... D15/140, 138; D13/40–41, 99; D10/77, 80; 357/79–80; 29/593; 324/158 F, 158 T, 156; D8/71; 269/89

[56] **References Cited**

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Primary Examiner—B. J. Bullock
Assistant Examiner—Ruth Takemoto
Attorney, Agent, or Firm—Freilich, Hornbaker, Rosen & Fernandez

[57] **CLAIM**

The ornamental design for a holder for testing an integrated circuit chip, as shown.

DESCRIPTION

FIG. **1** is a top, front, and right side perspective view of a holder for testing an integrated circuit chip showing my new design;

FIG. **2** is a bottom, rear, and left side perspective view thereof;

FIG. **3** is a left side elevational view thereof, the right side being a mirror image thereof;

FIG. **4** is a rear elevational view thereof; and

FIG. **5** is a front elevatioal view thereof.

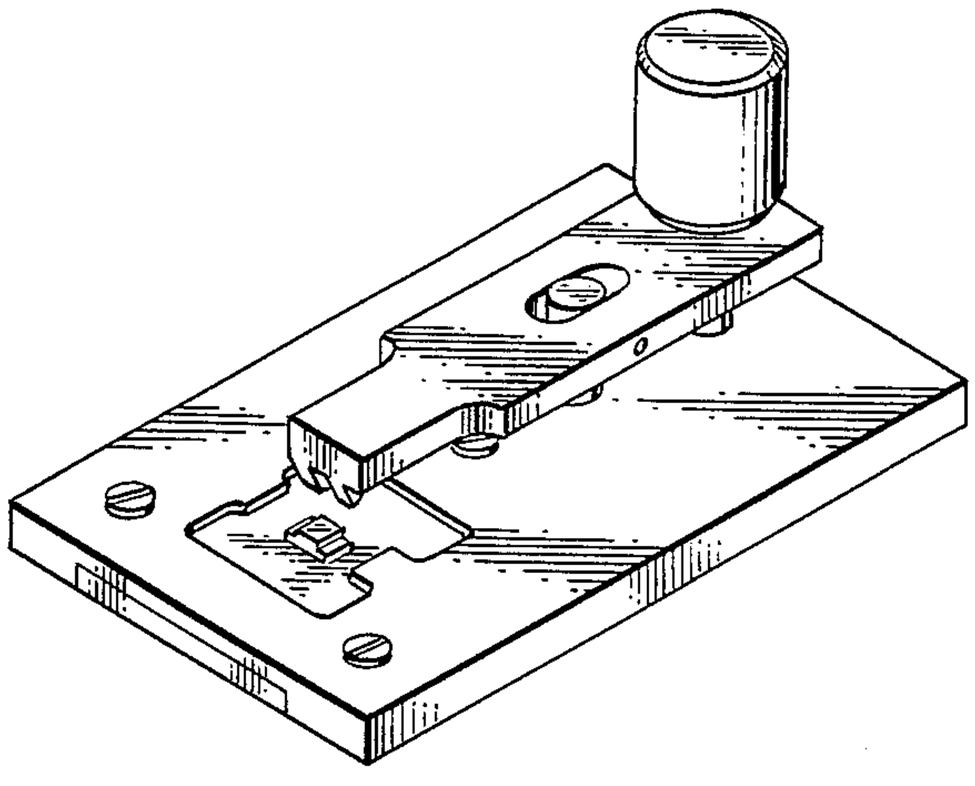


FIG. 1

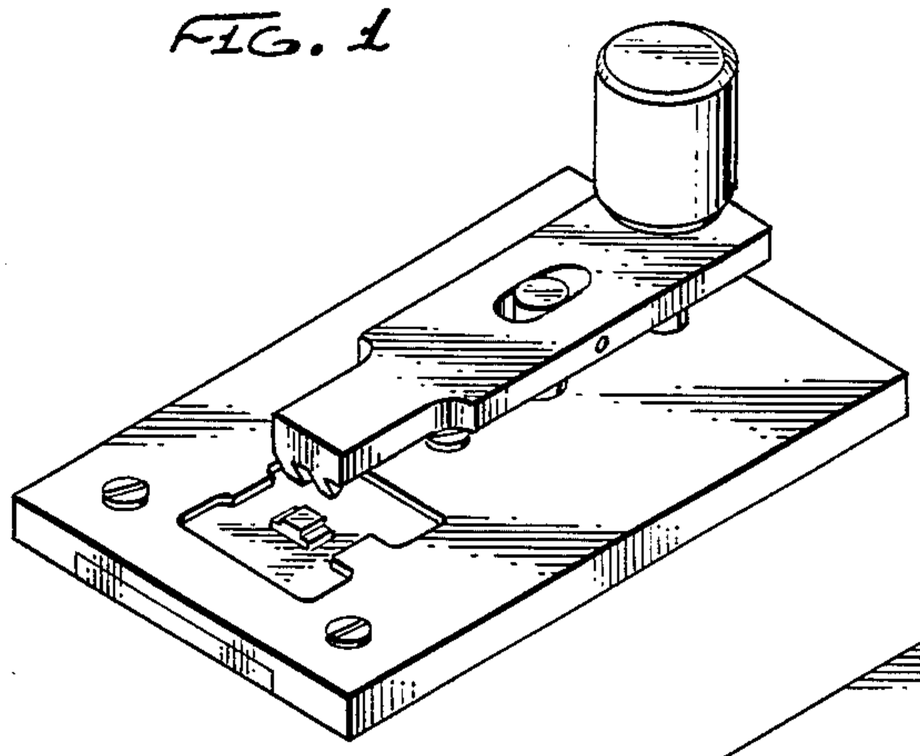
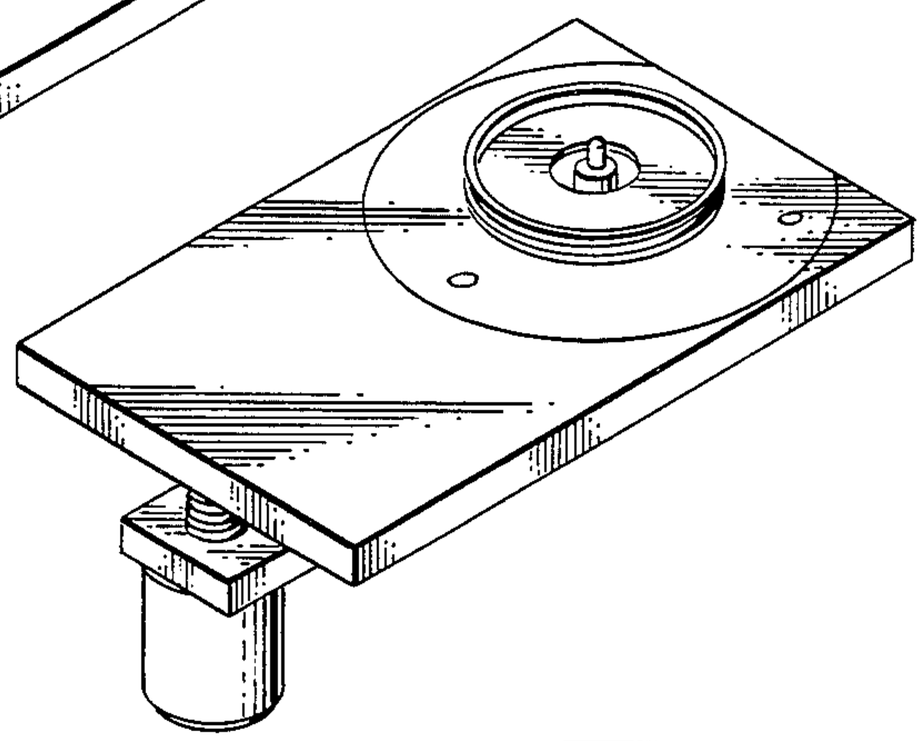


FIG. 2



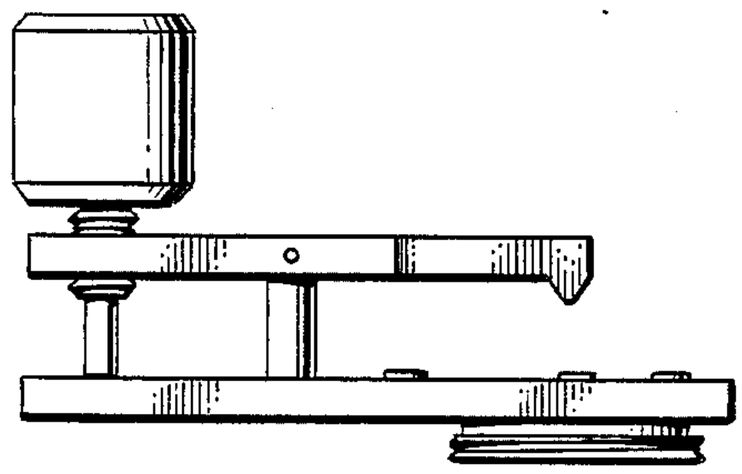


FIG. 3

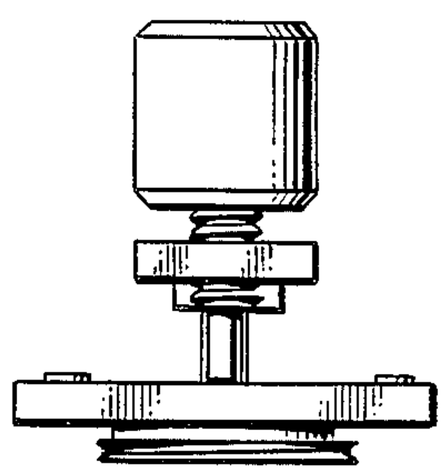


FIG. 4

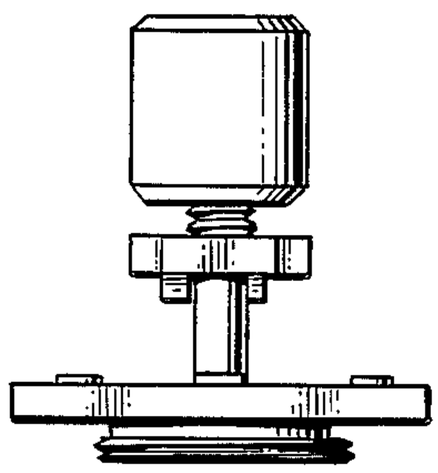


FIG. 5